

# STT2605

-4.0A, -30V, R<sub>DS(ON)</sub> 80mΩ

P-Channel Enhancement Mode Power Mos.FET

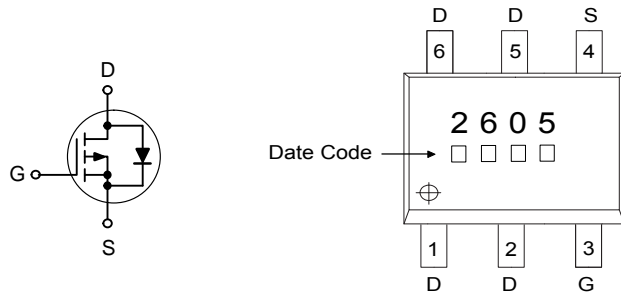
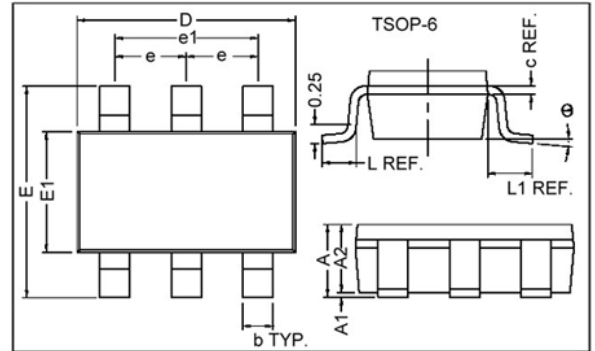
RoHS Compliant Product

## Description

The STT2605 utilized advance processing techniques to achieve the lowest possible on-resistance, extermely efficient and cost-effectiveness device. The STT2605 is universally used for all commercial-industrial applications.

## Features

- \* Fast Switching Characteristic
- \* Lower Gate Charge
- \* Small Footprint & Low Profile Package



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	1.10 MAX.		L	0.45 REF.	
A1	0	0.10	L1	0.60 REF.	
A2	0.70	1.00	□	0°	10°
c	0.12 REF.		b	0.30	0.50
D	2.70	3.10	e	0.95 REF.	
E	2.60	3.00	e1	1.90 REF.	
E1	1.40	1.80			

## Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V <sub>DS</sub>	-30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current, (Note 3)	I <sub>D</sub> @T <sub>A</sub> =25°C	-4.0	A
Continuous Drain Current, (Note 3)	I <sub>D</sub> @T <sub>A</sub> =70°C	-3.3	A
Pulsed Drain Current (Note 1)	I <sub>DM</sub>	-20	A
Total Power Dissipation	P <sub>D</sub> @T <sub>A</sub> =25°C	2.0	W
Linear Derating Factor		0.016	W/°C
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+150	°C

## Thermal Data

Parameter	Symbol	Ratings	Unit
Thermal Resistance Junction-ambient (Note 3)	R <sub>thj-a</sub>	62.5	°C/W

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## Electrical Characteristics( T<sub>j</sub>=25 °C Unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-30	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA
Breakdown Voltage Temp. Coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>j</sub>	-	-0.02	-	V/°C	Reference to 25°C, I <sub>D</sub> =-1mA
Gate Thershold Voltage	V <sub>GS(th)</sub>	-1.0	-	-3.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250uA
Gate-Source Leakage Current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> =±20V
Drain-Source Leakage Current (T <sub>j</sub> =25°C)	I <sub>DSS</sub>	-	-	-1	uA	V <sub>DS</sub> =-30V, V <sub>GS</sub> =0
Drain-Source Leakage Current (T <sub>j</sub> =55°C)		-	-	-25	uA	V <sub>DS</sub> =-24V, V <sub>GS</sub> =0
Static Drain-Source On-Resistance <sup>2</sup>	R <sub>DS(ON)</sub>	-	-	80	mΩ	V <sub>GS</sub> =-10V, I <sub>D</sub> =-4.0A
		-	-	120		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-3.0A
Total Gate Charge	Q <sub>g</sub>	-	5.5	8.8	nC	I <sub>D</sub> =-4.0A V <sub>DS</sub> =-24V V <sub>GS</sub> =-4.5V
Gate-Source Charge <sup>2</sup>	Q <sub>gs</sub>	-	1	-		
Gate-Drain ("Miller") Charge	Q <sub>gd</sub>	-	2.6	-		
Turn-on Delay Time <sup>2</sup>	T <sub>d(ON)</sub>	-	7	-	nS	V <sub>DD</sub> =-15V I <sub>D</sub> =-1A V <sub>GS</sub> =-10V R <sub>G</sub> =3.3Ω R <sub>D</sub> =15 Ω
Rise Time	T <sub>r</sub>	-	6	-		
Turn-off Delay Time	T <sub>d(OFF)</sub>	-	18	-		
Fall Time	T <sub>f</sub>	-	4	-		
Input Capacitance	C <sub>iss</sub>	-	400	640	pF	V <sub>GS</sub> =0V V <sub>DS</sub> =-25V f=1.0MHz
Output Capacitance	C <sub>oss</sub>	-	90	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	30	-		
Forward Transconductance	G <sub>fs</sub>	-	6	-	S	V <sub>DS</sub> =-5V, I <sub>D</sub> =-4.0A

## Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Forward On Voltage <sup>2</sup>	V <sub>DS</sub>	-	-	-1.2	V	I <sub>S</sub> =-1.6A, V <sub>GS</sub> =0V.
Reverse Recovery Time <sup>2</sup>	T <sub>rr</sub>	-	21	-	nS	I <sub>S</sub> =-4.0A, V <sub>GS</sub> =0V di/dt=100A/us
Reverse Recovery Charge	Q <sub>rr</sub>	-	14	-	nC	

Notes: 1.Pulse width limited by safe operating area.

2.Pulse width ≤300us, dutycycle≤2%.

3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board; 156°C/W when mounted on Min. copper pad.

### Characteristics Curve

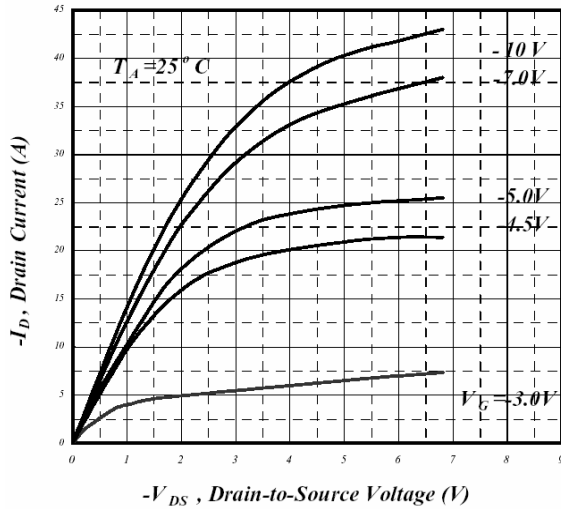


Fig 1. Typical Output Characteristics

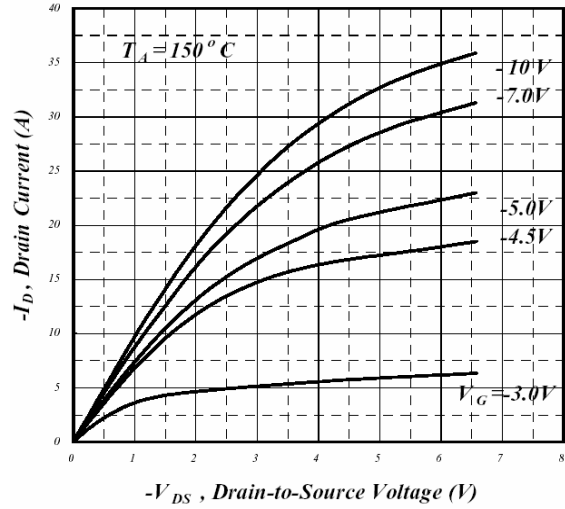


Fig 2. Typical Output Characteristics

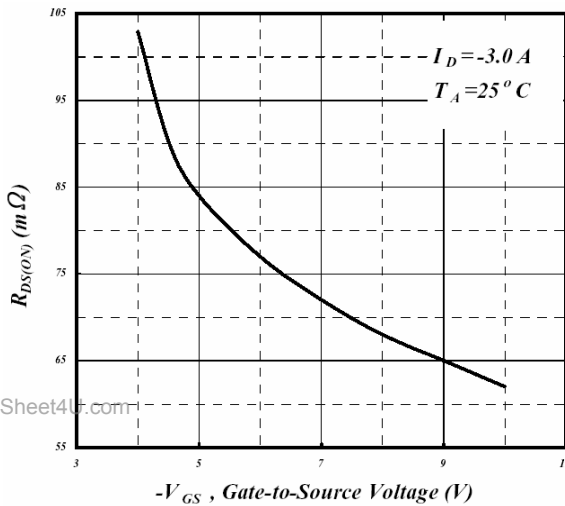


Fig 3. On-Resistance v.s. Gate Voltage

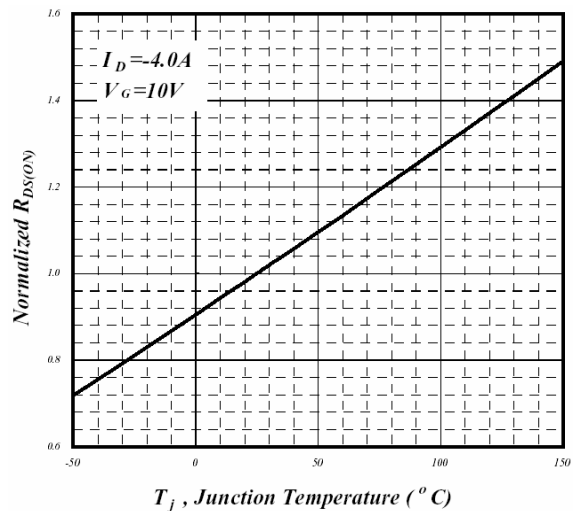


Fig 4. Normalized On-Resistance v.s. Junction Temperature

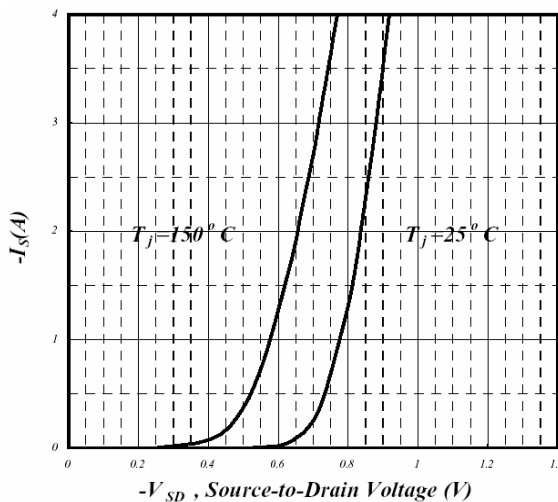


Fig 5. Forward Characteristics of Reverse Diode

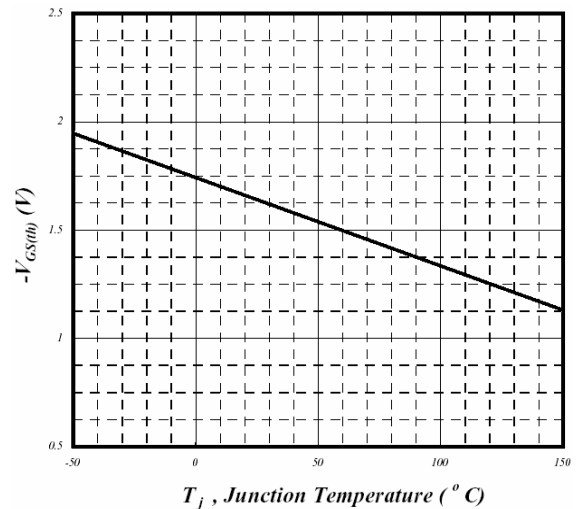
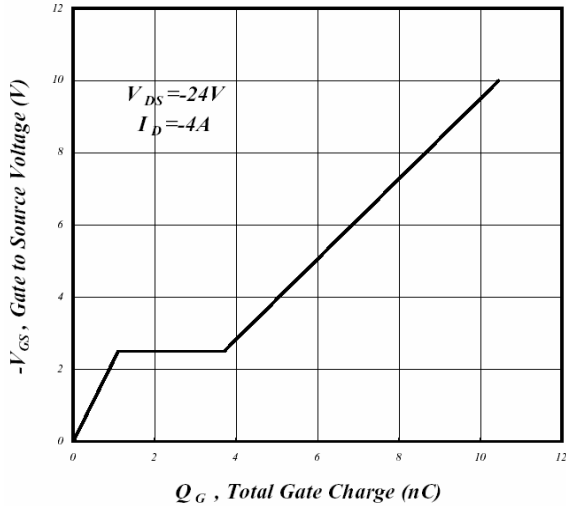
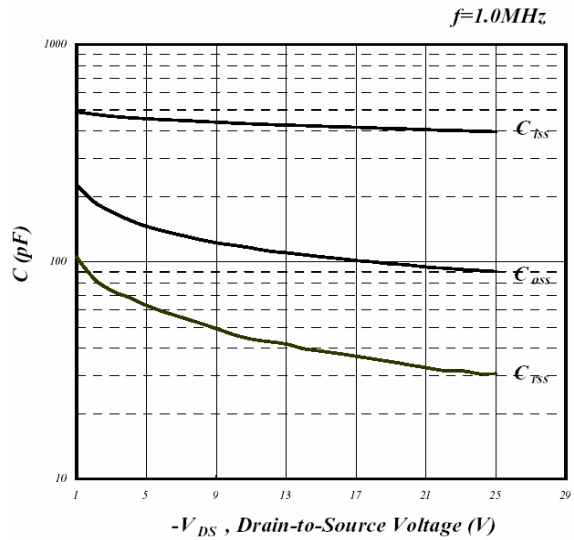


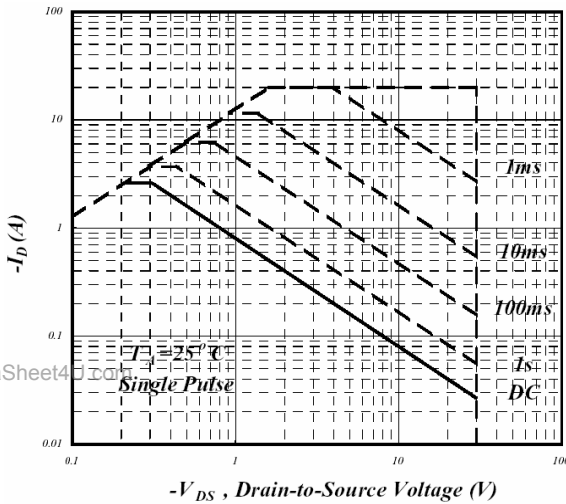
Fig 6. Gate Threshold Voltage v.s. Junction Temperature



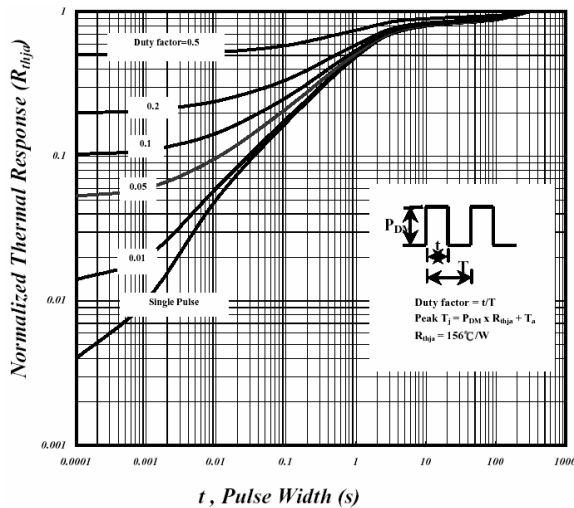
**Fig 7. Gate Charge Characteristics**



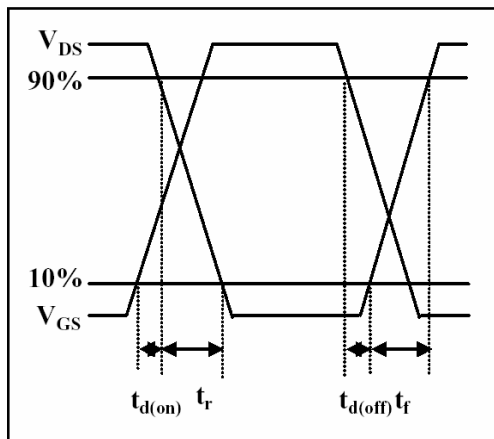
**Fig 8. Typical Capacitance Characteristics**



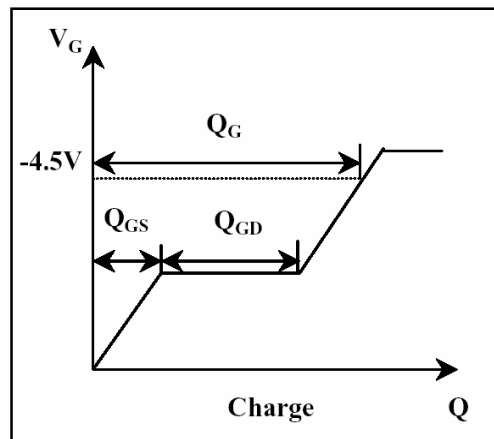
**Fig 9. Maximum Safe Operating Area**



**Fig 10. Effective Transient Thermal Impedance**



**Fig 11. Switching Time Waveform**



**Fig 12. Gate Charge Waveform**